Cleanliness Levels of NFF Equipment

1. Thermal Diffusion and Implantation Module

Process Code	Location	Equipment	Cleanliness level	Cleaning		
CVD						
CVD-A2	P2-01000	LPCVD-A2 Doped Amor-Si	Clean	A3+SRD-A		
CVD-A3	P2-01000	LPCVD-A3 Amor-Si/Poly	Clean	A3+SRD-A		
CVD-B1	P2-01000	LPCVD-B1 Low-Stress Nitride	Clean	A3+SRD-A		
CVD-B2	P2-01000	LPCVD-B2 Nitride	Clean	A3+SRD-A		
CVD-B3	P2-01000	LPCVD-B3 LTO	Clean	A3+SRD-A		
CVD-EPI	P2-01000	ET3000 Epitaxy	Clean	A3+SRD-A		
CVD-A4	P2-01000	LPCVD-A4 Si-Ge / Amor-Si / Poly	Semi-Clean	B1+SRD-B D1(dump-rinser)		
CVD-B4	P2-01000	LPCVD-B4 LTO / PSG	Semi-Clean	B1+SRD-B D1(dump-rinser)		
CVD-P1	P2-01000	310PC PECVD	Semi-Clean	B1+SRD-B D1(dump-rinser)		
CVD-TEOS	P2-01000	TEOS PECVD	Semi-Clean	B1+SRD-B D1(dump-rinser)		
CVD-P2	P2-01000	STS PECVD	Non-Standard	B1+SRD-B/D1(dump- rinser)/F(dump-rinser)		
CVD-CNT	P2-01000	CNT PECVD	Non-Standard	B1+SRD-B/D1(dump- rinser)/F(dump-rinser)		
CVD-ALD	P2-01000	Oxford ALD	Non-Standard	B1+SRD-B/D1(dump- rinser)/F(dump-rinser)		
		Thermal Diffusion	n			
DIF-C1	P2-01000	Diff. Furnace-C1 FGA Annealing	Non-Standard	B1+SRD-B/D1(dump- rinser)/F(dump-rinser)		
DIF-C2	P2-01000	Diff. Furnace-C2 N Pre-Deposition	Clean	A3+SRD-A		
DIF-C3	P2-01000	Diff. Furnace-C3 P Pre-Deposition	Clean	A3+SRD-A		
DIF-D1	P2-01000	Diff. Furnace-D1 Dry Oxidation	Clean (Only for gate oxide)	A3+SRD-A		
DIF-A1	P2-01000	Diff. Furnace-A1 Anneal/Oxidation	Clean	A3+SRD-A		
DIF-D2	P2-01000	Diff. Furnace-D2 Dry/Wet Oxidation	Clean	A3+SRD-A		
DIF-D3	P2-01000	Diff. Furnace-D3 Annealing/Dry/Wet Oxidation	Non-Standard	B1+SRD-B/D1(dump- rinser)/F(dump-rinser)		
DIF-F1	P2-01000	Diff. Furnace-F1 Annealing/Dry/Wet Oxidation	Semi-Clean	B1+SRD-B D1(dump-rinser)		
DIF-C4	P2-01000	Diff. Furnace-C4 FGA Annealing	Semi-Clean	B1+SRD-B D1(dump-rinser)		
DIF-R1	P2-01000	RTP-600S	Clean	A3+SRD- A		
DIF-R2	P2-01000	AG610 RTP	Semi-Clean	B1+SRD-B D1(dump-rinser)		
DIF-R3	EC-01000	AW610 RTP	Non-Standard	M1 (dump-rinser)+ N2 dry		
		Implantation				
IMP-3000	P2-01000	CF-3000 Implanter	Clean/Semi-Clean			

2. Dry Etching and Sputtering Module

* Remark: For Semi-Clean process of "ICP for Poly Silicon Etching", please contact NFF technicians.

Process Code	Location	Equipment	Cleanliness level	Remark
		Dry Etching		
DRY-AOE	P2-01000	AOE Etcher	Clean	
DRY-Si-1	P2-01000	DRIE Etcher #1	Clean	
DRY-Si-2	Rm. 2223	DRIE Etcher #2	Clean/Semi-Clean	
DRY-Si-3	Rm. 2223	DRIE Etcher #3	Non-Standard	
DRY-490	P2-01000	Lam 490 Etcher	Clean	
DRY-Poly	P2-01000	Poly Etcher	Clean/Semi-Clean *	
DRY-XeF2	P2-01000	XeF2 Silicon Etcher	Clean/Semi-Clean	
DRY-Trion	P2-01000	Trion RIE Etcher	Semi-Clean	
DRY-Metal-1	P2-01000	AST Metal Etcher	Semi-Clean	
DRY-Metal-2	P2-01000	Oxford Aluminum Etcher	Semi-Clean	
DRY-GaN	P2-01000	GaN Etcher	Non-Standard	
DRY-RIE-1	EC-01000	Oxford RIE Etcher	Non-Standard	
DRY-RIE-2	P2-01000	NFF RIE Etcher	Clean/Semi-Clean	
DRY-Cleaner	P2-01000	Diener Plasma Cleaner	Non-Standard	Microfluidic user only
		Photoresist O ₂ As	sher	
DRY-PR-1	P2-01000	PS210 Asher	Clean	
DRY-PR-2	P2-01000	IPC 3000 Asher #1	Semi-Clean	
DRY-PR-3	P2-01000	IPC 3000 Asher #2	Non-Standard	
DRY-PR-4	EC-01000	IPC 3000 Asher #3	Non-Standard	
		Sputtering & Evapo	ration	
SPT-3180	P2-01000	Varian 3180 Sputter	Semi-Clean	
SPT-NSC3000	P2-01000	NSC3000 Sputter	Semi-Clean	
SPT-EV1	P2-01000	Cooke Evaporator #1	Semi-Clean	
SPT-ARC	P2-01000	ARC-12M Sputter	Non-Standard	
SPT-CVC	P2-01000	CVC-601 Sputter	Non-Standard	
SPT-Denton	EC-01000	Denton Sputter	Non-Standard	
SPT-EV2	EC-01000	Cooke Evaporator #2	Non-Standard	
SPT-AST600	EC-01000	AST 600EI Evaporator	Non-Standard	
SPT-AST450	EC-01000	AST 450I Evaporator	Non-Standard	

3. Wet Etching and CMP Module

Process Code	Location	Equipment	Cleanliness Level	Remark
	•	СМР	•	
CMP-1	P2-10000	Strasbaugh CMP	Clean	
CMP-2	P2-10000	USI Wafer Cleaner	Clean	
CMP-3	Rm. 2227	Silicon Grinder	Semi-Clean	
CMP-4	Rm. 2227	Buehler Polisher #1	Semi-Clean	
CMP-5	Rm. 2227	Buehler Polisher #2	Non-Standard	
	•	Wet-station		•
Wetstation A - Su	Ifuric Cleaning	Station		
WET-A1	P2-01000	A1: Sulfuric Cleaning (NFF reserved)	Clean	
WET-A2	P2-01000	A2:HF:H20 (1:50)	Clean	
WET-A3	P2-01000	A3: Sulfuric Cleaning	Clean	Only for "Clean" furnace and RTP
SRD-A	P2-01000	Spin Dryer-A	Clean	
Wetstation B - Su	Ifuric Cleaning/	Decontamination Station		
WET-B1	P2-01000	B1:Sulfuric Cleaning	Clean	Not for "Clean" furnace and RTP
WET-B2	P2-01000	B2:HF:H20(1:50)	Clean	
WET-B3	P2-01000	B3:Decontamination	Clean	
SRD-B	P2-01000	Spin Dryer-B	Clean	
Wetstation C - Ox	ide/Nitride Etch	ing Station		
WET-C1	P2-01000	C1:Nitride Strip	Clean	
WET-C2	P2-01000	C2:Oxide Deglaze/PSG Removal	Clean	
WET-C3	P2-01000	C3:BOE	Clean	
SRD-C	P2-01000	Spin Dryer-C	Clean	
Wetstation D - Se	mi-Clean Metal	Processing Station		
WET-D1	P2-01000	D1:Aluminum Etch	Semi-Clean	
WET-D2	P2-01000	D2:HF:H2O(1:100) MILC	Semi-Clean	
WET-D3	P2-01000	D3:General Purpose	Semi-Clean	
WET-D4	P2-01000	D4:Sulfuric Cleaning for MILC	Semi-Clean	
SRD-D	P2-01000	Spin Dryer-D	Semi-Clean	
Wetstation E - Se	mi-Clean Non-N	letal Processing Station		
WET-E1	P2-01000	E1:ITO Etch	Semi-Clean	
WET-E2	P2-01000	E2:General Purpose	Semi-Clean	
WET-E3	P2-01000	E3:HF:H2O(1:100)	Semi-Clean	
WET-E4	P2-01000	E4:Resist Strip	Clean/Semi- Clean	
SRD-E	P2-01000	Spin Dryer-E	Clean/Semi- Clean	
Wetstation F - No	n-Standard Pro	cessing Station		
WET-F1	P2-01000	F1:General Purpose	Non-Standard	
WET-F2	P2-01000	F2:General Purpose	Non-Standard	
WET-F3	P2-01000	F3:General Purpose	Non-Standard	
SRD-F	P2-01000	Spin Dryer-F	Non-Standard	

Process Code	Location	Equipment	Cleanliness Level	Remark			
Wetstation G - TMAH Etching Station							
WET-G1	P2-01000	G1:TMAH	Clean				
WET-G2	P2-01000	G2:TMAH	Clean				
SRD-G	P2-01000	Spin Dryer-G	Clean				
Wetstation J - TM	Wetstation J - TMAH/KOH Etching Station						
WET-J1	P2-01000	J1:TMAH/KOH Etching	Non-Standard				
WET-J2	P2-01000	J2:TMAH/KOH Etching	Non-Standard				
Wetstation M - No	n-Standard Org	anic Solvent Station					
WET-M1	EC-01000	M1:MS2001 Resist Strip	Non-Standard				
WET-M2	EC-01000	Branson 5510	Non-Standard				
WET-M3	EC-01000	M3:MS2001 Mask Cleaning	Non-Standard				
Wetstation O - No	n-Standard Hyd	rochloric Acid Etch Station					
WET-O1	EC-01000	O1: HCI	Non-Standard				
Wetstation W - No	n-Standard Org	anic Solvent Station					
WET-W1	P2-00100	W1:MS2001 Resist Strip	Non-Standard				
WET-W2	P2-00100	W2:FHD-5	Non-Standard				
SRD-W	P2-00100	Spin Dryer-W	Non-Standard				
Wetstation X - Cle	an Organic Solv	ent Station					
WET-X1	P2-00100	X1:General Purpose	Clean				
WET-X2	P2-00100	X2:General Purpose	Clean				
Wetstation Y - Ser	mi-Clean Organi	c Solvent Station					
WET-Y1	P2-00100	Y1:MS2001 Resist Strip	Semi-Clean				
WET-Y2	P2-00100	Y2:MS2001 Mask Cleaning	Semi-Clean				
SRD-Y	P2-00100	Spin Dryer-Y	Semi-Clean				
Wetstation Z - Semi-Clean/Non-Standard Organic Solvent Station							
WET-Z1	P2-00100	Z1:FHD-5	Semi-Clean				
WET-Z2	P2-00100	Z2:Dump Rinser	Semi-Clean/Non- Standard				
Critical Point Dryer							
CPD-1	NDL-10000	Critical Point Dryer	Semi-Clean				
Electroplating							
EP-1	Rm. 2227	Copper Electroplating	Non-Standard				

4. Photolithography Module

Process Code	Location	Equipment	Cleanliness Level	Remark
		Ultrasonic Bath	•	
PHT-U1	P2-00100	Branson 5510	Semi-Clean	
PHT-U2	P2-00100	Branson 3510	Non-Standard	
		Stepper/Aligner and Bon	der	
PHT-A7	P2-00100	Karl Suss MA6 #2	Clean/Semi-Clean	
PHT-S1	P2-00100	ASML Stepper	Clean/Semi-Clean	
PHT-A1	P2-00100	AB-M Aligner #1(UV)/(DUV)	Semi-Clean/Non- Standard	
PHT-A2	P2-00100	AB-M Aligner #2(UV)	Semi-Clean/Non- Standard	
PHT-A5	EC-01000	Karl Suss MA6 #1	Non-Standard	
PHT-B1	P2-00100	Karl Suss Bonder SB6	Non-Standard	
EMW-1	EC-01000	JEOL JBX-6300FS E-Beam Lithography System	All Level	
PHT-P1	P2-01000	Nanoscribe 3D printer	All Level	
		Coater and Track		
PHT-T1	P2-00100	SVG88 Coater Track	Clean/Semi-Clean	
PHT-T2	P2-00100	SVG88 Developer Track	Clean/Semi-Clean	
PHT-SC3	P2-00100	CEE Coater	Clean/Semi-Clean	
PHT-SC1	P2-00100	SUSS Coater	Semi-Clean/Non- Standard	
PHT-SC2	P2-00100	Desktop Coater	Non-Standard	
PHT-SC5	P2-00100	EVG Spray Coater	All Level	
PHT-SC4	EC-01000	Solitec Coater #1	Non-Standard	
PHT-SC6	P2-01000	Laurell PDMS Coater	Non-Standard	Microfluidic user only
PHT-MX1	P2-01000	Kurabo PDMS Mixer/Deaerator	Non-Standard	Microfluidic user only
		Oven		
PHT-O3	P2-00100	Imperial V (105C)	Clean/Semi-Clean	
PHT-O4	P2-00100	Oven-C (120C)	Clean/Semi-Clean	
PHT-O6	P2-00100	Oven-A (180C)	Clean/Semi-Clean	
PHT-O7	P2-00100	Oven-B (80C)	Clean/Semi-Clean	
PHT-O1	P2-00100	Grieve	Non-Standard	
PHT-O2	P2-00100	Shellab (120C)	Non-Standard	
PHT-O5	P2-00100	Vacuum Oven	Non-Standard	
PHT-O8	EC-01000	Oven-D (120C)	Non-Standard	
PHT-O9	EC-01000	Oven-E (105C)	Non-Standard	
		Hotplate		
PHT-HP1	P2-00100	Sawatec Hot Plate	Clean/Semi-Clean	
PHT-HP2	P2-00100	SUSS Hot Plate	Clean/Semi-Clean	
PHT-HP9	P2-00100	CEE Hot Plate #1(110C)	Clean/Semi-Clean	
PHT-HP3	P2-00100	Hot Plate-C	Non-Standard	
PHT-HP4	P2-00100	Hot Plate-D	Non-Standard	
PHT-HP5	EC-01000	EMS Hot Plate #1 (50C)	Non-Standard	
PHT-HP6	EC-01000	CEE Hot Plate #2 (90C)	Non-Standard	
PHT-HP7	EC-01000	Hot Plate (110C)	Non-Standard	
PHT-HP8	P2-00100	EMS Hot Plate #2 (50C)	Non-Standard	

Process Code	Location	Equipment	Cleanliness Level	Remark		
	HMDS Primer					
PHT-HM1	P2-00100	HMDS Primer #1	Non-Standard			
PHT-HM2	P2-00100	HMDS Primer #2	Clean/Semi-Clean			
PHT-HM3	EC-01000	HMDS Primer #3	Non-Standard			

Remark:

- Equipment in NFF-EC (EC-01000)
- Equipment in NFF-Phase 2 (P2-01000 and P2-00100)
- Equipment in TSV Process Laboratory (Rm. 2227)
- Equipment in Deep RIE Process Center (Rm. 2223)
- Equipment in NFF-Phase 2 for Microfluidic Process (P2-01000)
- Equipment in Nanofabrication Demonstration Laboratory (NDL) (Rm.3114)